

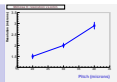
M.i.p. detection performances of a 100 μ s read-out CMOS pixel sensor with digitised outputs

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on behalf of IPHC and IRFU/Saclay

OUTLINE

- Strategy of the chip development (reminder)
- Column parallel sensor prototyping : *Objectives of MIMOSA-22 prototyping – Lab & beam test results*
- The question of radiation tolerance
- SUZE-01 zero suppression μ circuit : *Established performances*
- First chip with integrated zero suppression: status and plans
- Summary - Outlook



■ Specific goals of MIMOSA-22 :

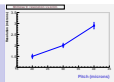
- ⇒ *validate the fast read-out architecture developed in MIMOSA-16 (next slide) at Real Scale*
- ⇒ *extract an optimal pixel design (sensing diode and signal processing μ circuits)*
- ⇒ *improve the chip testability (JTAG, analog outputs, pads, ...)*

■ 2 sensor versions designed and fabricated :

- ⇒ *MIMOSA-22 : mainly for overall pixel architecture definition*
- ⇒ *MIMOSA-22bis : robustness, fine tuned optimisation, radiation tolerance*

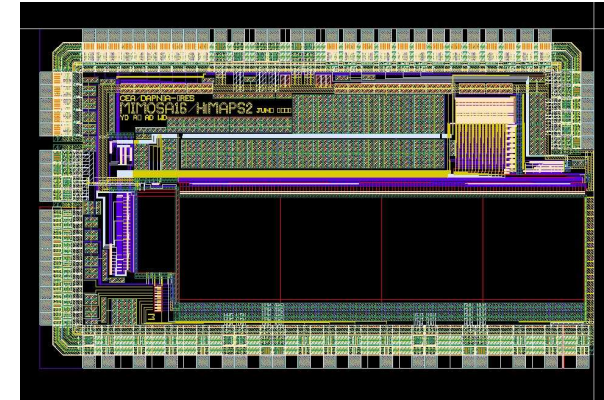
■ Objectives beyond MIMOSA-22:

- ⇒ *Variant (MIMOSA-23) with 640 x 640 pixels (30 μ m pitch), 640 μ s r.o. time, for STAR HFT 1st upgrade*
 - ⇒ *sent for fabrication in November '08* ⇒ *expected to produce (charm) physics in 2010*
- ⇒ *Merge MIMOSA-22 architecture with \emptyset μ circuit (SUZE-01)*
 - 1) *Final sensor (MIMOSA-26) for EUDET BT* ⇒ *to be sent for fabrication on Friday 21st*
 - ↪ *Will equip the EUDET beam telescope (6 planes) in Spring 2009*
 - 2) *Final sensor for STAR Vx Det. (suited to VXD outer layers)* ⇒ *fab. end of 2009*
 - ↪ *expected to produce (charm) physics in 2011*



- Performances of a Small Prototype with Digitised Output

- MIMOSA-16 :
 - ◇ fabricated in 2006 (coll. with IRFU/Saclay)
 - ◇ 32 col. of 128 pixels (25 μm pitch, integrated CDS)
 - ◇ 24 col. ended with an integrated discriminator
 - ◇ 4 different pixels (i.e. 4 sub-arrays)

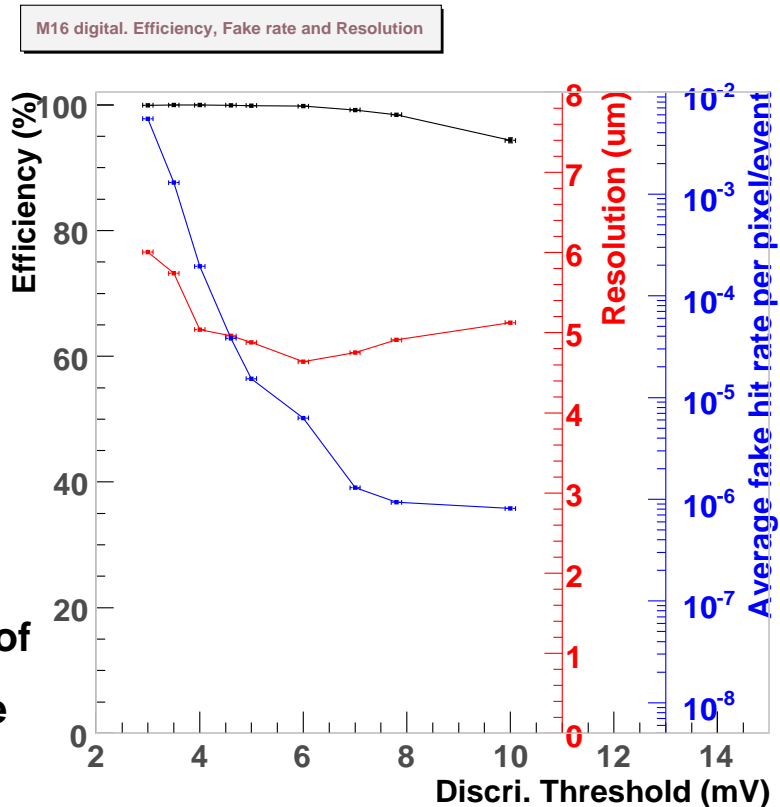


■ Tests at CERN-SPS ($\sim 180 \text{ GeV } \pi^-$) in Summer 2007

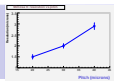
→ results of one sub-array (S4)



Discri. threshold	Detection eff.	Fake rate	Resolution
4 mV	$99.96 \pm 0.03 \text{ (stat) } \%$	$\sim 2 \cdot 10^{-4}$	$\sim 4.8 - 5.0 \mu m$
6 mV	$99.88 \pm 0.05 \text{ (stat) } \%$	$< 10^{-5}$	$\sim 4.6 \mu m$



▷▷▷ Architectures of pixel (integrated CDS) and of full chain made of "columns ended with integrated discri." validated at small scale



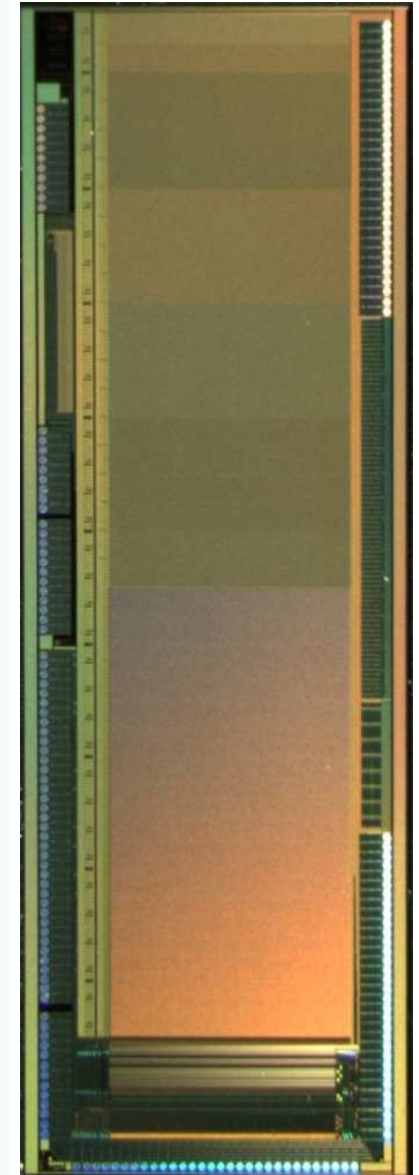
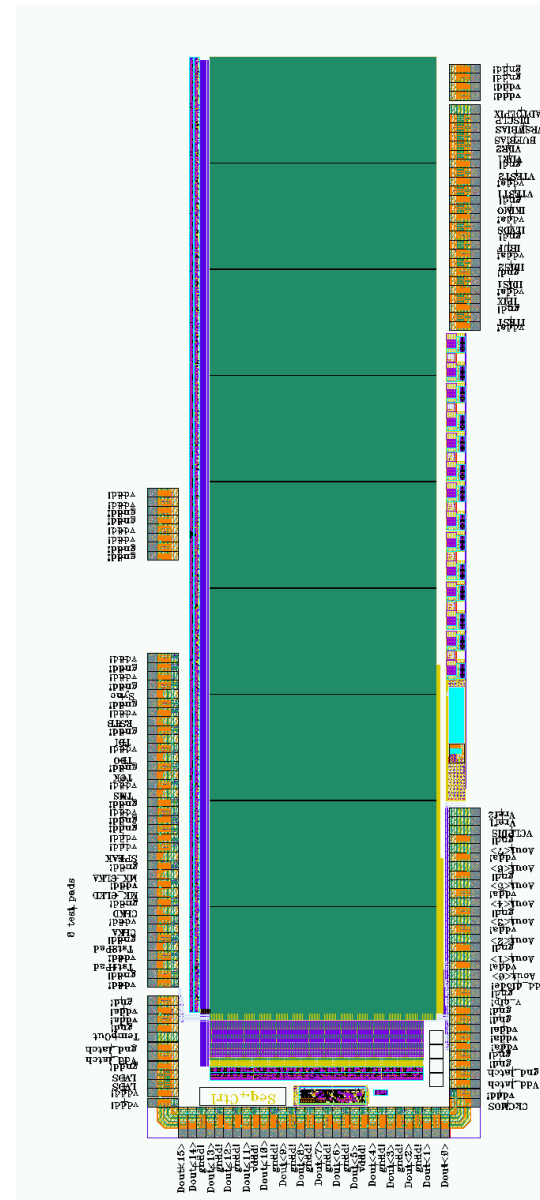
♣ Extension of MIMOSA-16 \rightarrow larger surface, smaller pitch, optimised pixel, JTAG, more testability

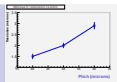
Pixel characteristics (optimal charge coll. diode size ?) :

- * pitch : $18.4 \mu m$ (compromise resolution/pixel layout)
- * diode surface : $\sim 10 - 20 \mu m^2$ to optimise charge coll. & gain
- * 128 columns ended with discriminator
- * 576 pixels per column (\equiv final column length)
- * 8 columns with analog output for test purposes
- * 9 sub-matrices of 64 rows :
 - 17 pixel designs w/o ionising rad. tol. diode
 - \Rightarrow active digital area $\sim 25 mm^2$ (128 x 576 pixels)
- * read-out time $\sim 100 \mu s$ ($\sim 10^4$ frames/s)

Testability :

- * JTAG + bias DAC \rightarrow programmable chip steering
- * 2 additional DC voltages to emulate pixel's output for independent discriminator performance assessment
- * output frequency ≤ 40 MHz

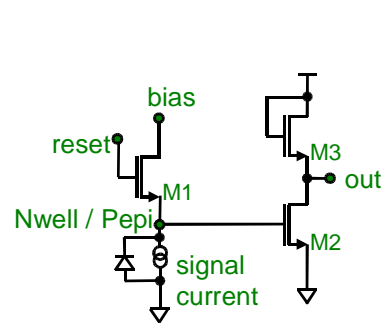




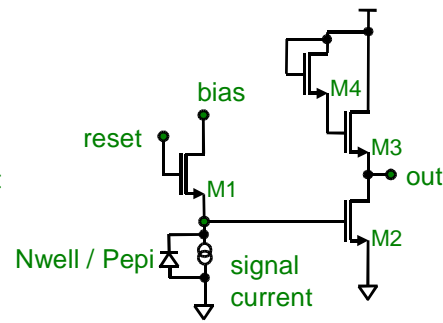
Various pixel designs (rad. tol. and standard) :

✧ *reset diode (improved gain)*

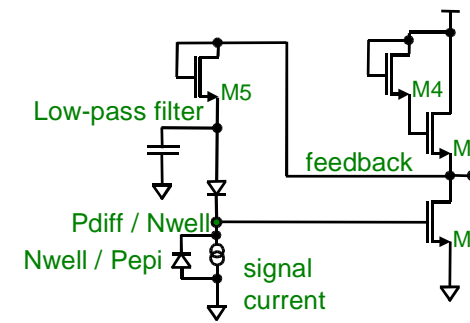
✧ *self-biased diode with feedback (improved gain)*



(S13)



(S10)



(S6)

Main results obtained with exposure to ^{55}Fe source ($t_{r.o.} = 92.5 \mu\text{s}$) :

✧ *Noise :*

≈ *Temporal (pixel) Noise* $\sim 0.5 - 0.7 \text{ mV}$ ($10 < N < 14 e^- \text{ ENC}$)

≈ *FPN* $\sim 0.25 \text{ mV}$

≈ *N (rad. tol. pixels)* $\sim N$ (*standard pixels*) $+ 1 e^- \text{ ENC}$

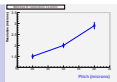
✧ *Cluster CCE :*

≈ *3x3 pixels* : 70 – 80 %

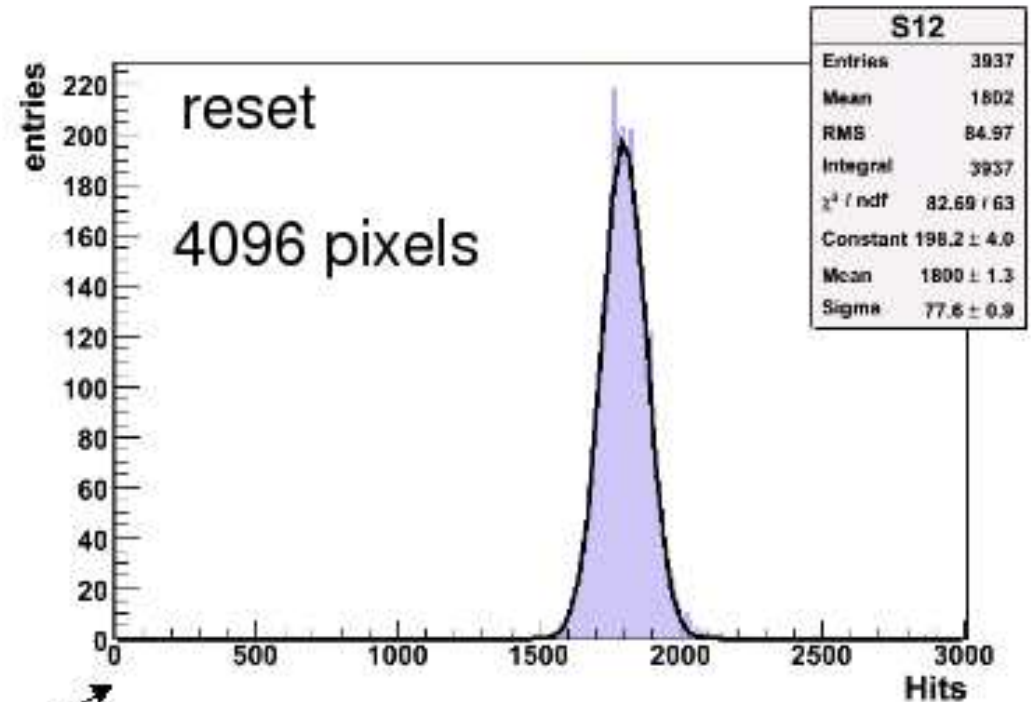
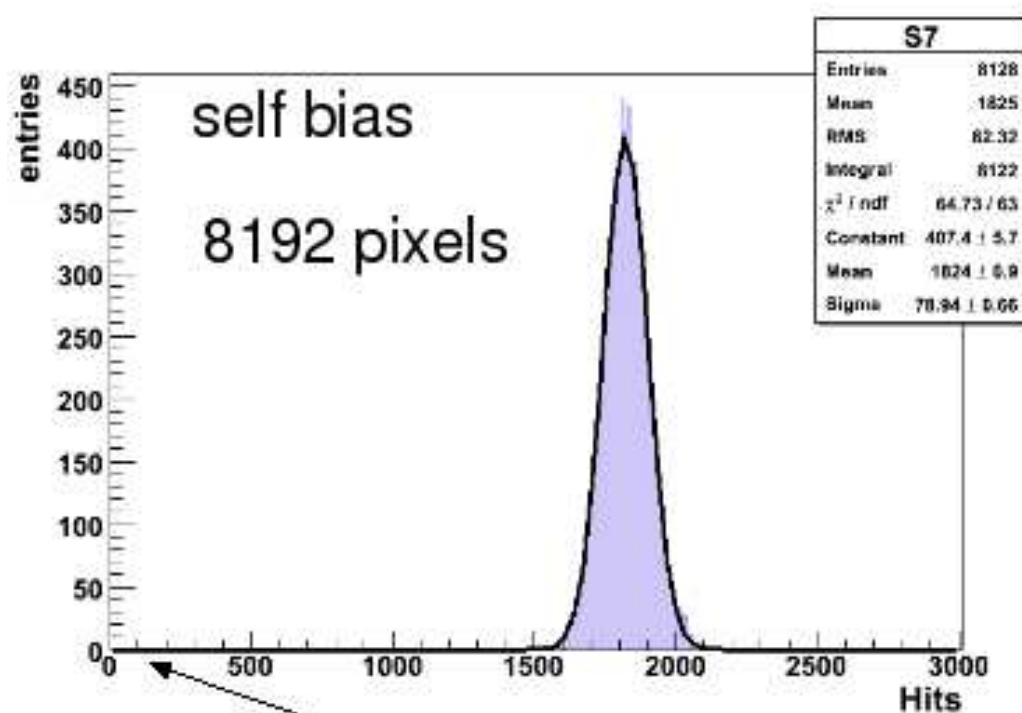
≈ *5x5 pixels* : 80 – 90 %

✧ *modest T dependence between* $\sim 10^\circ \text{C}$ *and* 35°C : $\lesssim 10\%$ *noise variation*

✧ *5 different chips characterised : identical performances within* $\pm 5\%$

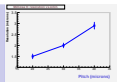


5 mV threshold with ^{55}Fe source



No dead pixel number

Good uniformity of discriminator response, within 4%



4 weeks of beam time at CERN-SPS :

- ▷ ~ 2 weeks in August with MIMOSA-22 (EUDET period)
- ▷ ~ 2 weeks in Sept.-Oct. with MIMOSA-22bis (SiLC period)

T4-H6 beam line : ~ 120 GeV π^- beam

▷▷▷▷

Chips mounted at center of Si-strip telescope

(4 pairs of orthogonal strips)

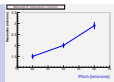
▷▷▷▷

2 MIMOSA-22 and 4 MIMOSA-22bis chips tested

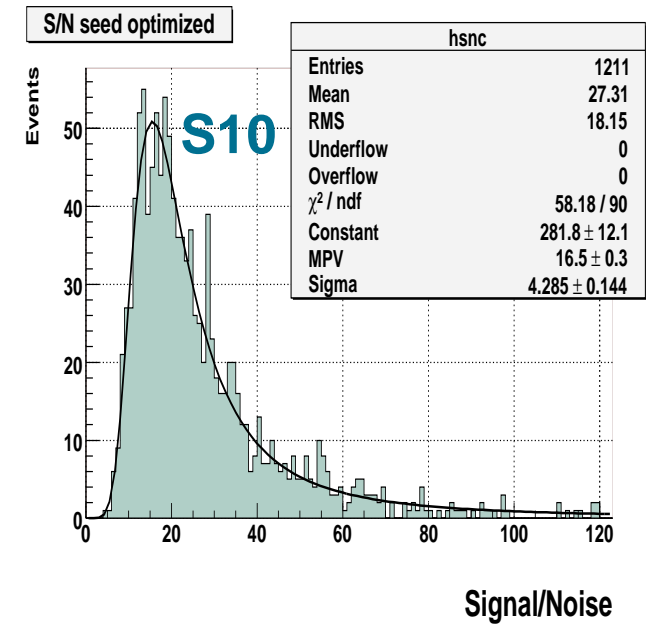
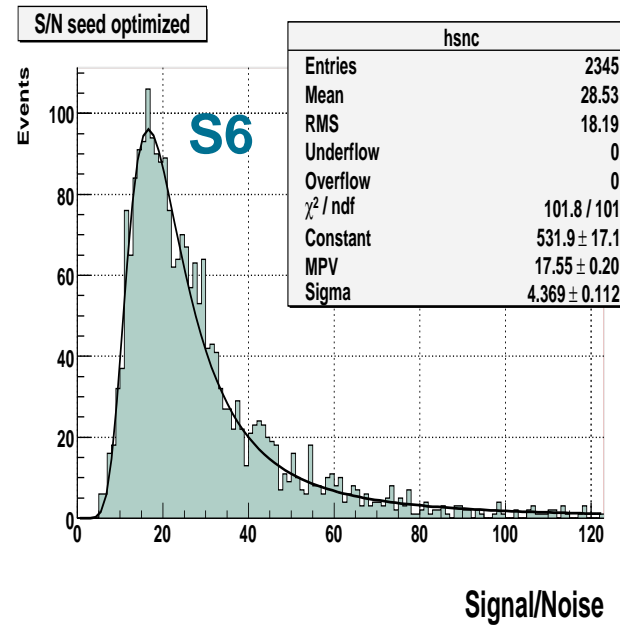
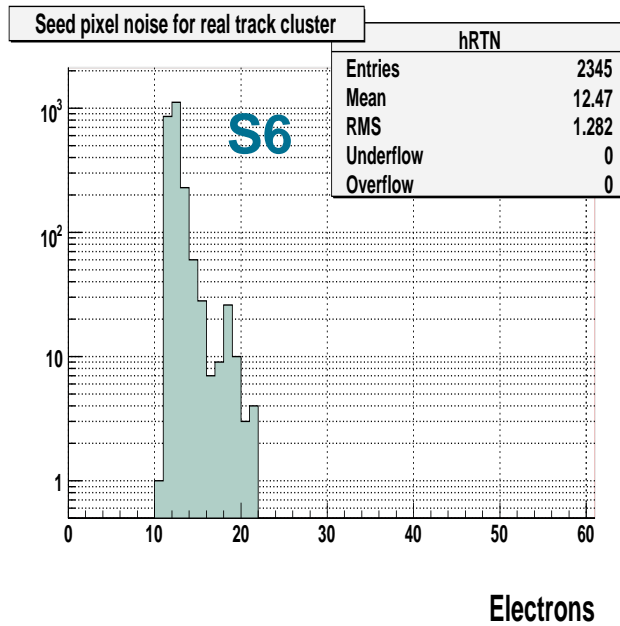
at several values of discriminator threshold

> 1 million tracks reconstructed in the sensors





Noise and S/N (seed pixel) distributions delivered by the 8 columns without discriminator

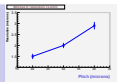


Detection performances (det. eff. , N and S/N for hits where the seed pixel exhibits $S/N > 4$) :

Sub-array	S6	S7	S8	S9	S10	S12	S13
Det. eff.	99.93 % ± 0.05 %	99.95 % ± 0.04 %	100.00 % +0/-0.30 %	100.00 % +0/-0.14 %	99.87 % ± 0.09 %	100.00 % +0/-0.08 %	100.00 % +0/-0.07 %
N ($e^- \text{ ENC}$)	12.5 ± 0.1	11.6 ± 0.1	12.3 ± 0.1	10.6 ± 0.1	13.6 ± 0.1	12.1 ± 0.1	14.0 ± 0.1
S/N (seed, MPV)	17.6 ± 0.2	18.5 ± 0.2	20.9 ± 1.1	19.5 ± 0.5	16.5 ± 0.3	18.2 ± 0.3	16.0 ± 0.3

✳ very satisfactory performances (det. eff. ~ 99.9 % and single pt resolution $\lesssim 1.5 \mu m$)

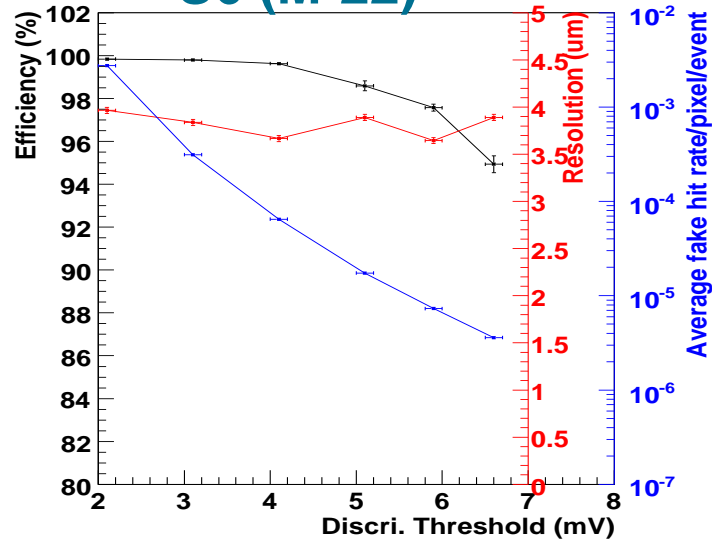
⇒ pixel architecture (diode size, rad. tol. diode design, amplification scheme) validated



■ Det. eff., fake hit rate & spatial resolution for S6 & S10 (M-22) and S2 (M-22bis) vs discri. threshold :

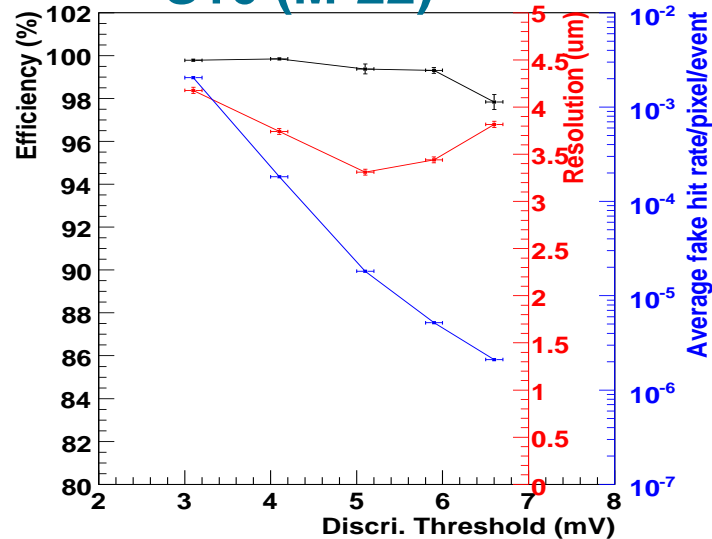
M22 digital S6. Efficiency, Fake rate and Resolution

S6 (M-22)



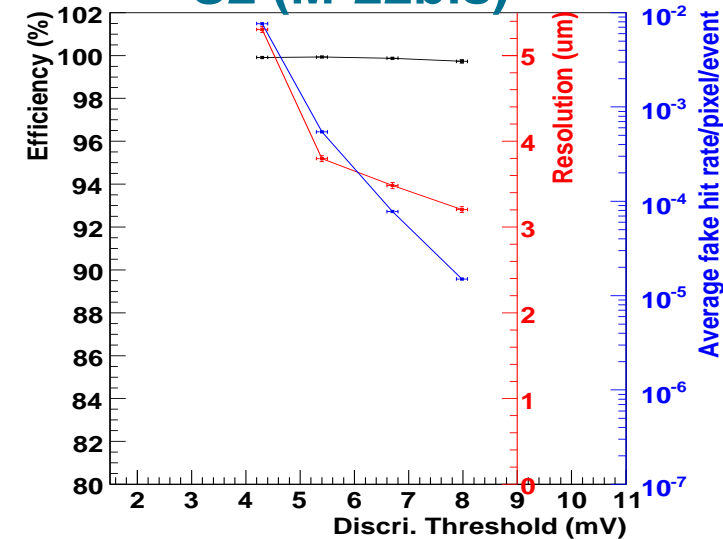
M22 digital S10. Efficiency, Fake rate and Resolution

S10 (M-22)



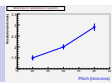
M22bis digital S2. Efficiency, Fake rate and Resolution

S2 (M-22bis)



■ Main results:

- * rather marginal performance differences between > 10 diff. pixels (e.g. rad. tol. vs standard)
- * det. eff. of analog output $\sim 99.9\%$ for all sub-arrays \Rightarrow pixel architecture validated
- * det. eff. of digital output $\gtrsim 99.8\%$ for almost all sub-arrays (agrees with MIMOSA-16)
- * fake hit rate very low ($O(10^{-4} - 10^{-5})$) while det. eff. still near 100%
- * (binary) single point resolution $\gtrsim 3.5 \mu\text{m}$ (as expected)
- * no performance non-uniformity observed over the chip surface \Rightarrow real scale check validated



The Question of Radiation Tolerance

Requirements:

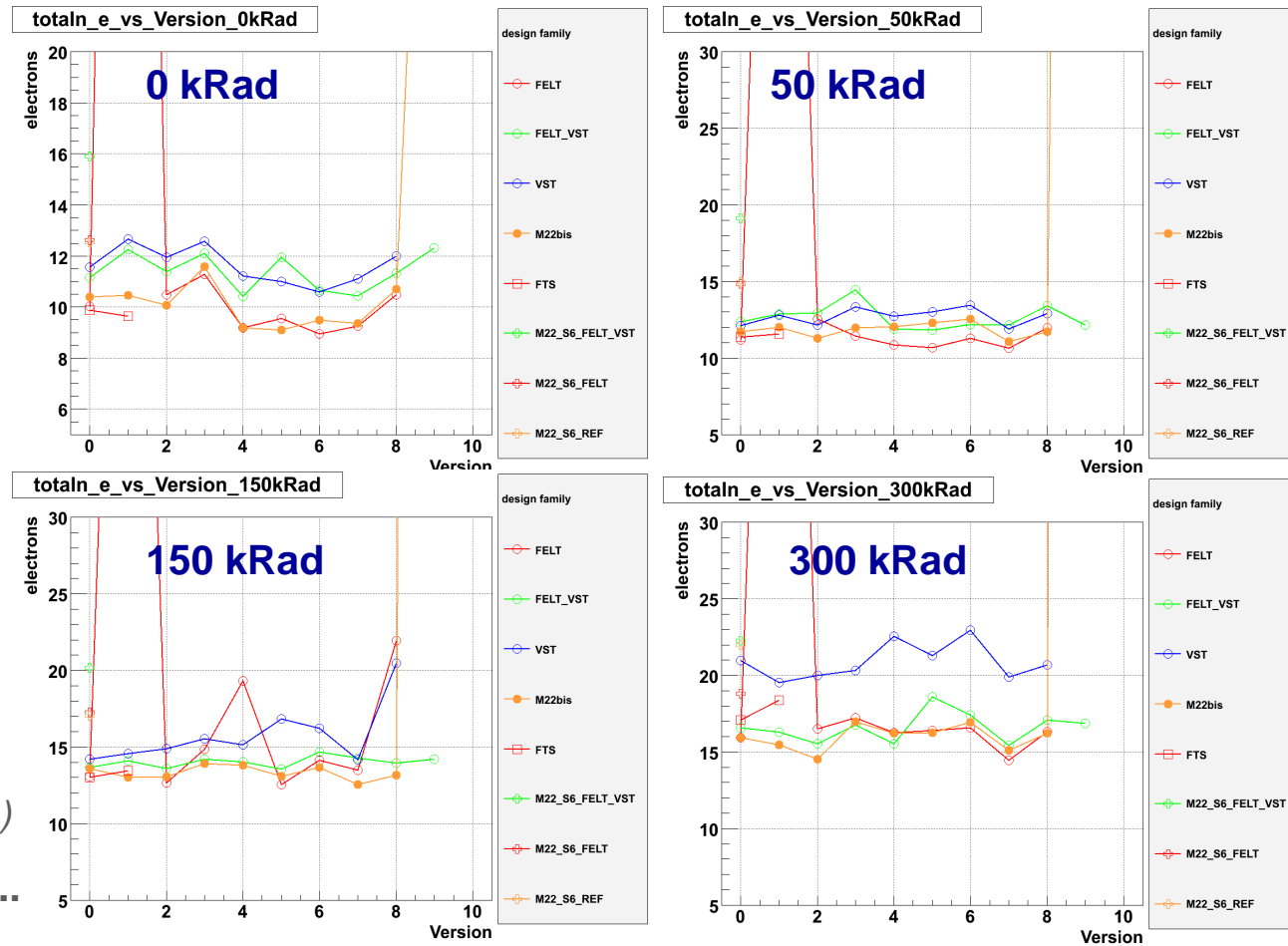
✳ **beamstrahlung (GuineaPig X 2) :** $\lesssim 10^3 e_{BS}^{\pm}/cm^2/25 \mu s \rightsquigarrow \lesssim 2 \cdot 10^{12} e_{BS}^{\pm}/cm^2/yr$
 $\hookrightarrow O(100) \text{ kRad/yr} - O(10^{11}) n_{eq}/cm^2/yr \text{ (NIEL } \sim 1/30)$

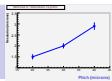
Assessing rad. tolerance (10 keV X-Rays) in lab.:

▷ ex. of S6 (M22) variants at + 20° C

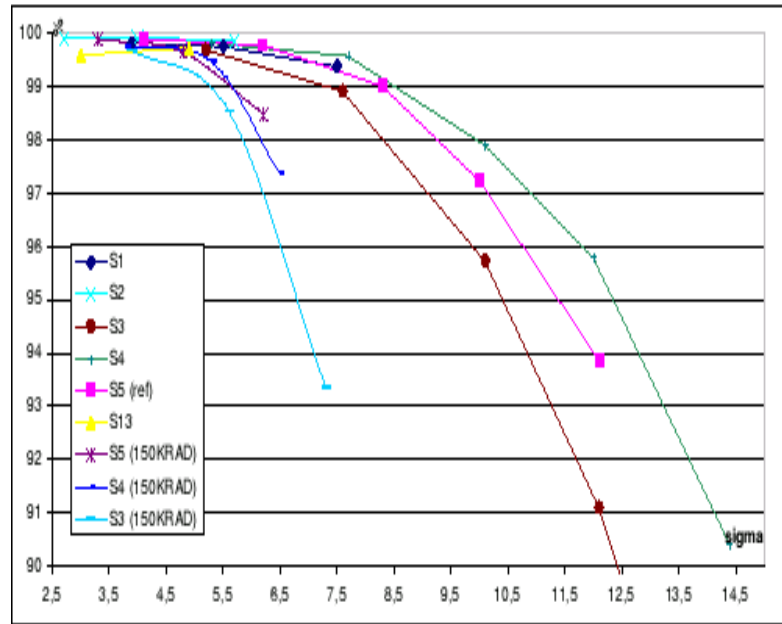
- ✳ before irradiation $\gtrsim 9.5 e^- \text{ ENC}$
- ✳ after 50 kRad $\gtrsim 11 e^- \text{ ENC}$
- ✳ after 150 kRad $\gtrsim 13 e^- \text{ ENC}$
- ✳ after 300 kRad $\gtrsim 15 e^- \text{ ENC}$

▷▷▷ **Excellent noise performance**
(but source of noise increase still under study)
 ... watch Charge Collection Efficiency ...





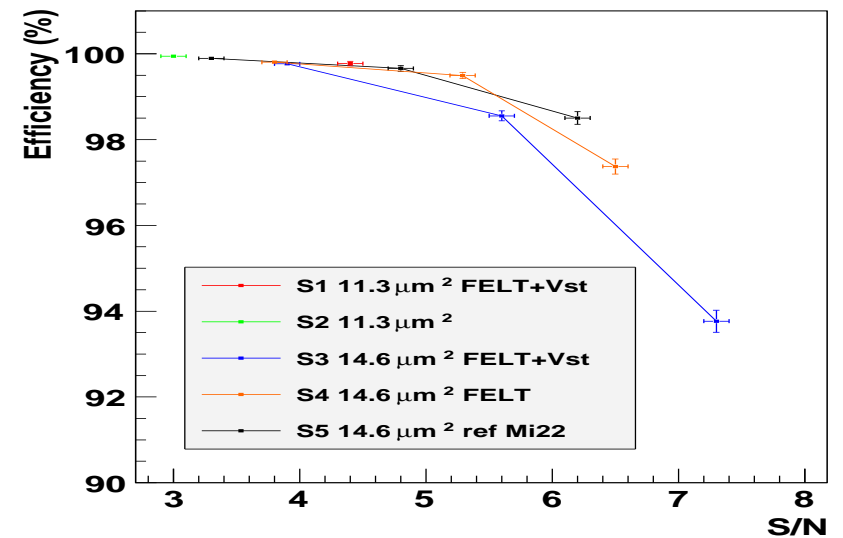
Beam test results with chips irradiated with 150 kRad :



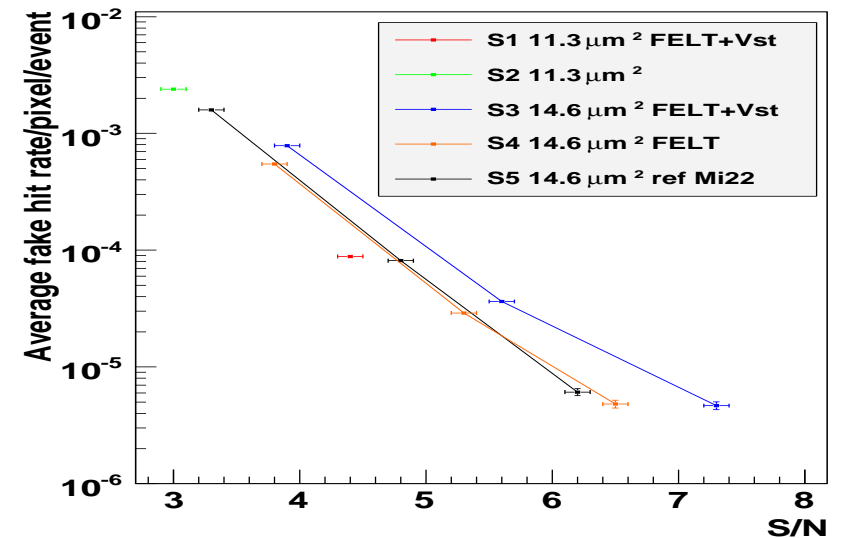
Det. eff. vs SNR before and after irradiation (150 kRad)

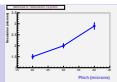
Pixel & column parallel architecture
with integrated discriminators
Fully Validated !!!

M22bis digital Efficiency after 150kRad



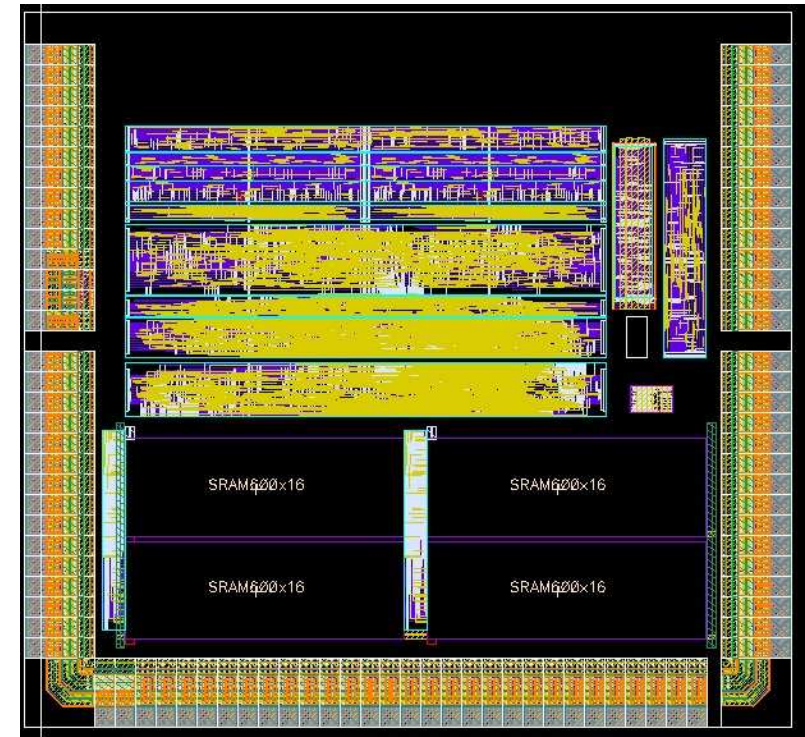
M22bis digital fake hit rate





■ 1st chip (SUZE-01) with integrated \emptyset and output memories (no pixels) :

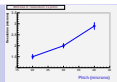
- ✧ 2 step, row by row, logic :
 - ◇ step-1 (inside blocks of 64 columns) :
 - identify up to 6 series of ≤ 4 neighbour pixels per row
 - delivering signal $>$ discriminator threshold
 - ◇ step-2 : read-out outcome of step-1 in all blocks
 - and keep up to 9 series of ≤ 4 neighbour pixels
- ✧ 4 output memories (512x16 bits) taken from AMS I.P. lib.
- ✧ surface $\sim 3.9 \times 3.6 \text{ mm}^2$



■ Test results summary :

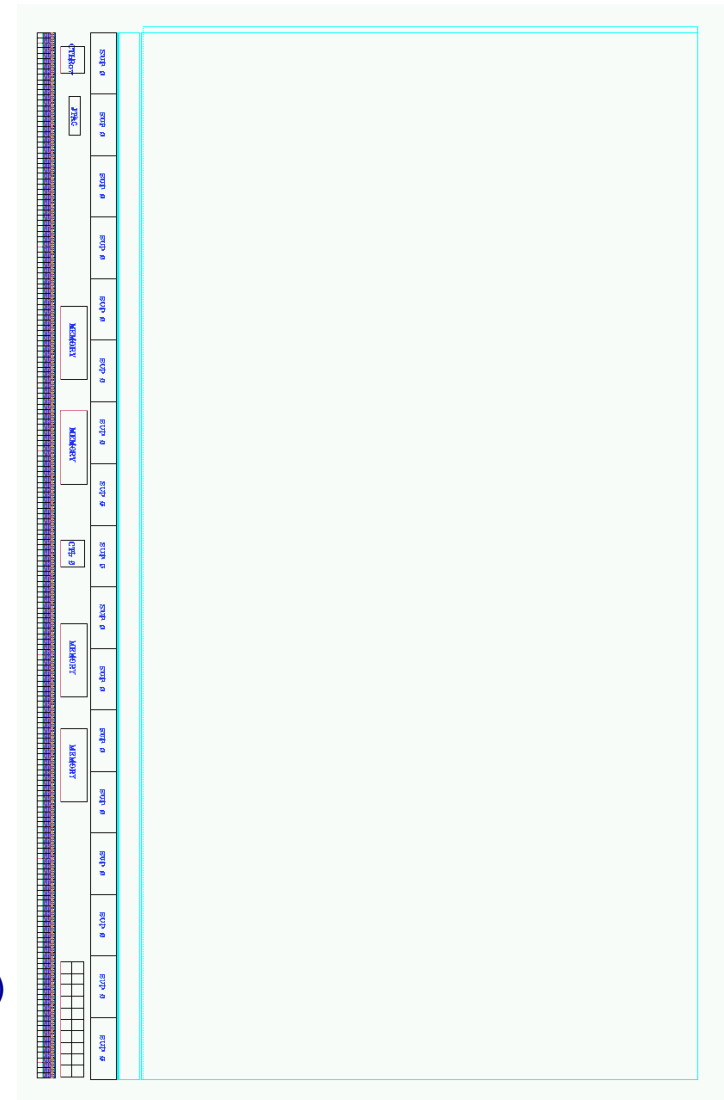
- ✧ back from foundry end of Sept. '07 \rightarrow (lab) tests completed
- ✧ design performances reproduced up to $1.15 \times$ design read-out frequency (T_{room}) :
 - noise values as predicted, no pattern encoding error, can handle > 100 hits/frame at rate $> 10^4$ frames/s

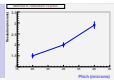
■ Still to do : evaluate radiation tolerance (latch-up) of output memories



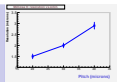
■ **Novembre 2008 : fabrication of MIMOSA-26 = Final Sensor for EUDET BT**

- ✳ **M-22 (binary outputs) complemented with \emptyset (SUZE-01)**
- ✳ **best performing (rad. tol.) pixel architecture of M-22(bis)**
 ↪ S5 pixel of MIMOSA-22bis
- ✳ **Active surface : 1152 columns of 576 pixels (21.2 x 10.6 mm²)**
 ↪ **extension of M-22 & SUZE-01 from 128 col. to 9 x 128 col.**
- ✳ **Pixel pitch : 18.4 μm \rightarrow \sim 0.7 million pixels**
 ↪ $\sigma_{sp} \gtrsim 3.5 \mu\text{m}$
- ✳ **Integration time \sim 110 μs \rightarrow \sim 10⁴ frames / second**
- ✳ \emptyset based on 18 groups of 64 columns and assuming \leq 9 "clusters" per row
- ✳ **Chip dimensions : \sim 21 x 12 mm²**
- ✳ **Data throughput: 1 output at \geq 80 Mbits/s or 2 outputs at \geq 40 Mbits/s**
- ✳ **Engineering run : 2 (+ \leq 4) wafers of \gtrsim 30 chips expected (if yield \sim 50 %)**
- ✳ **Design nearly completed \Rightarrow submission this Friday**





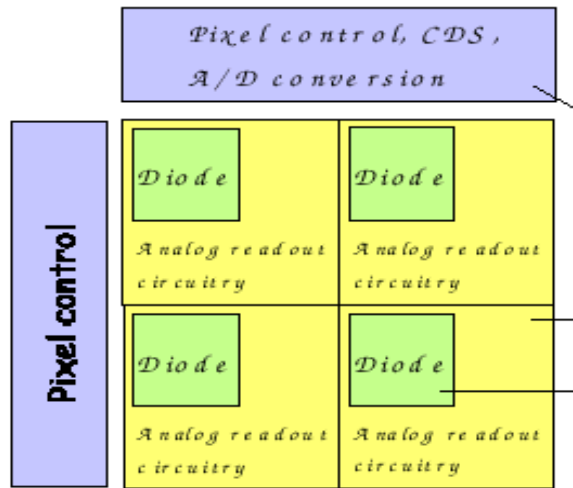
- Col. // architecture with discri. outputs validated for m.i.p. detection on real scale (128 col. of 576 pix.) :
 - ⇒ read-out frequency $\sim 10^4$ frames/s ✓
 - ⇒ pixel noise $\sim 10\text{--}13 e^- ENC \Rightarrow S/N \sim 17\text{--}22$ (MPV) ✓
 - ⇒ $\epsilon_{det} > 99.5\%$ with fake rate $\sim O(10^{-4} - 10^{-5})$, similar to MIMOSA-16 ✓
 - ⇒ $\sigma_{sp} \gtrsim 3.5 \mu m \Rightarrow 14 \mu m$ pitch would be sufficient for $3 \mu m$ resolution demanded for VXD ✓
 - ⇒ ionising rad. tol. \sim sufficient for VXD innermost layer (3 yrs ???) ✓
- ⇒ **2x2 cm² variant (30 μm pitch, 640 μs r.o.time) for STAR Vx Det. 1st upgrade**
 - ⇒ Being fabricated ⇒ (charm) physics in 2010
- ⇒ **MIMOSA-26 \equiv final sensor for EUDET BT ((combining col. // architecture with \emptyset μ -circuit) :**
 - ⇒ design \sim completed ⇒ submission on Friday Nov. 21st '08
 - ↪ tests expected to start in January 2009 ⇒ sensors mounted on BT in Spring '09
- ⇒ **Extension of MIMOSA-26: final sensor for STAR Vx Det. upgrade (OK for VXD out layers)**
 - ⇒ Fabrication end of 2009 ⇒ (charm) physics in 2011
- ⇒ **New step in 2009 (coll. with FNAL & INFN): 1st prototypes in 3D technology**
 - ↪ 2-tier & 3-tier devices, single & mixed CMOS techno., continuous & delayed r.o.



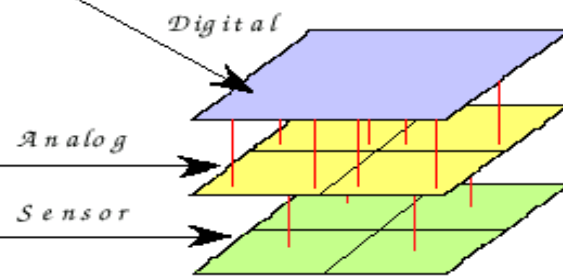
- **3DIT are expected to be particularly beneficial for CMOS sensors :**
 - *combine different fab. processes*
 - *alleviate constraints on transistor type inside pixel*

- **Split signal collection and processing fonctionnalités :**
 - *Tier-1: charge collection system*
 - *Tier-2: analog signal processing*
 - *Tier-3: mixed and digital signal processing*
 - *Tier-4: data formatting (electro-optical conversion ?)*

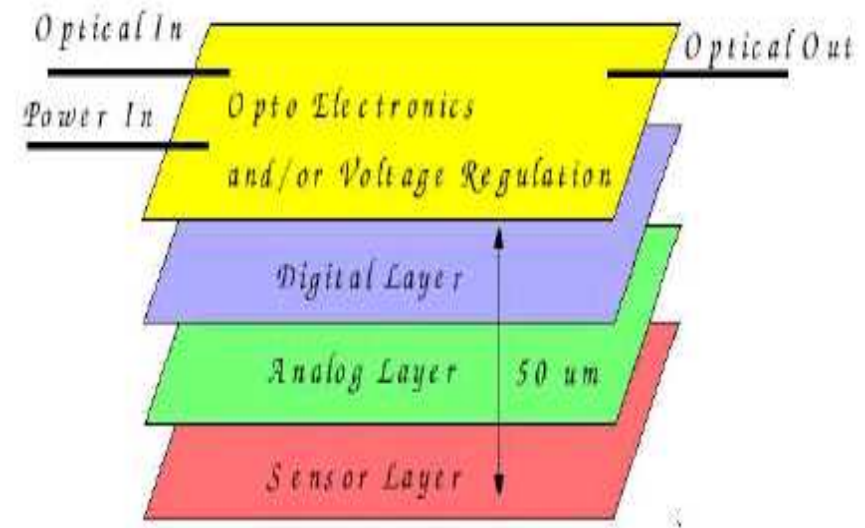
- **Use best suited technology for each Tier :**
 - *Tier-1: epitaxy, deep N-well ?*
 - *Tier-2: analog, low leakage current, process (nb of metal layers)*
 - *Tier-3 & -4 : digital process (nb of metal layers), feature size → fast laser (VOCSEL) driver, etc.*

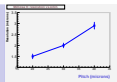


Conventional MAPS 4 Pixel Layout



3D 4 Pixel Layout





■ 2009 : 1st MIMOSA sensors in 3DIT

✳ *fab. technology : Chartered - Tezzaron*

✳ *130 nm – 2 Tiers*

✳ *Several collaborators sharing the reticule, coordinated by FNAL :*

• FNAL • INFN labs • IN2P3 labs • IRFU/Saclay

✳ *2 types of devices :* • 2-Tier single CMOS • 3-Tier mixed CMOS

■ combine MIMOSA design (IPHC) with VIP (FNAL)

